Download Kindle

APPLICATION OF PELLETRON ACCELERATOR TO STUDY TOTAL DOSE RADIATION

Condition: New. Publisher/Verlag: LAP Lambert Academic Publishing | Effects on MOS and Bipolar Devices | The exposure of metal-oxide-semiconductor (MOS) and bipolar devices to the ionizing radiation induces interface and oxide trapped charge in the field oxide, in addition to point defects. These radiations induced trapped charges and defects degrade the electrical characteristics of the devices. In order to use MOS and bipolar devices in space and other radiation rich environments, the devices need to withstand a few krad to...

Read PDF Application of Pelletron Accelerator to Study Total Dose Radiation

- Authored by A. P., Gnana Prakash / Nagarj, Pushpa
- Released at -



Filesize: 2.28 MB

Reviews

Without doubt, this is actually the very best function by any article writer. it was writtern quite flawlessly and valuable. Once you begin to read the book, it is extremely difficult to leave it before concluding.

-- Prof. Isobel Heller MD

A whole new e-book with an all new viewpoint. I could possibly comprehended every little thing using this created e pdf. I am just very happy to inform you that this is the greatest book i have read through within my own life and could be he best pdf for ever. -- Hank Treutel

Very beneficial to all of category of folks. We have read through and i am sure that i will going to read once again once again in the future. Your daily life span will probably be change when you full reading this pdf. -- Amelia Roob DDS